

#### **Description**

The VSM60N08 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications.

#### **General Features**

•  $V_{DS} = 80V, I_D = 60A$  $R_{DS(ON)} < 12 \text{ m}\Omega @ V_{GS} = 10V$  (Typ:9mΩ)

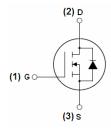
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Special designed for convertors and power controls
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

#### **Application**

- Power switching application
- Hard switched and High frequency circuits
- Uninterruptible power supply



TO-252



Schematic Diagram

## **Package Marking and Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VSM60N08-T2	VSM60N08	TO-252	-	-	-

#### Absolute Maximum Ratings (T<sub>A</sub>=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	VDS	80	V	
Gate-Source Voltage	V <sub>G</sub> s	±20	V	
Drain Current-Continuous	I <sub>D</sub>	60	А	
Drain Current-Continuous(T <sub>C</sub> =100°C)	I <sub>D</sub> (100℃)	42.4	Α	
Pulsed Drain Current <sup>(Note 1)</sup>	I <sub>DM</sub>	240	Α	
Maximum Power Dissipation	P <sub>D</sub>	130	W	
Derating factor		0.87	W/℃	
Single pulse avalanche energy (Note 5)	E <sub>AS</sub>	380	mJ	
Operating Junction and Storage Temperature Range	T <sub>J</sub> ,T <sub>STG</sub>	-55 To 175	$^{\circ}$ C	



Shenzhen VSEEI Semiconductor Co., Ltd

#### **Thermal Characteristic**

Thermal Resistance, Junction-to-Case (Note 2)	R <sub>eJC</sub>	1.15	°C/W	
---	------------------	------	------	--

## Electrical Characteristics (T<sub>A</sub>=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics				•		•
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250µA	80	-	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =80V,V <sub>GS</sub> =0V	-	-	1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	$V_{GS}$ =±20 $V$ , $V_{DS}$ =0 $V$	-	-	±100	nA
On Characteristics (Note 3)			•	•		
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS},I_{D}=250\mu A$	2	3	4	V
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =20A	-	9	12	mΩ
Forward Transconductance	<b>g</b> FS	V <sub>DS</sub> =5V,I <sub>D</sub> =20A	-	30	-	S
Dynamic Characteristics (Note4)				•		•
Input Capacitance	C <sub>lss</sub>	V <sub>DS</sub> =25V,V <sub>GS</sub> =0V,	-	4414	-	PF
Output Capacitance	C <sub>oss</sub>		-	219	-	PF
Reverse Transfer Capacitance	C <sub>rss</sub>	F=1.0MHz	-	188	-	PF
Switching Characteristics (Note 4)	1		1			•
Turn-on Delay Time	t <sub>d(on)</sub>		-	19	-	nS
Turn-on Rise Time	t <sub>r</sub>	$V_{DD}$ =40V, $R_L$ =15Ω $R_G$ =2.5Ω, $V_{GS}$ =10V	-	12	-	nS
Turn-Off Delay Time	t <sub>d(off)</sub>		-	40	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	15	-	nS
Total Gate Charge	Qg	1/ 401/1 004	-	81.5	-	nC
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}$ =40V, $I_D$ =20A,	-	26.9	-	nC
Gate-Drain Charge	Q <sub>gd</sub>	V <sub>GS</sub> =10V	-	23.7	-	nC
Drain-Source Diode Characteristics	1			I		I.
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =20A	_	-	1.2	V
Diode Forward Current (Note 2)	Is		-	-	60	Α
Reverse Recovery Time	t <sub>rr</sub>	Tj=25°C,I <sub>F</sub> =20A	-	36	-	nS
Reverse Recovery Charge	Qrr	di/dt=100A/µs <sup>(Note3)</sup>	-	54	-	nC

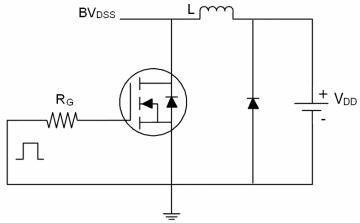
## Notes:

- **1.** Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production
- **5.** EAS condition: Tj=25 $^{\circ}$ C,V<sub>DD</sub>=40V,V<sub>G</sub>=10V,L=0.5mH,Rg=25 $\Omega$

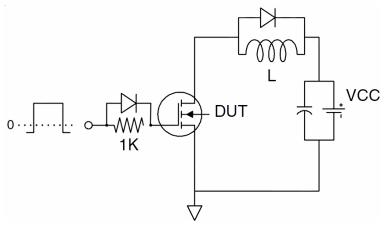


# **Test Circuit**

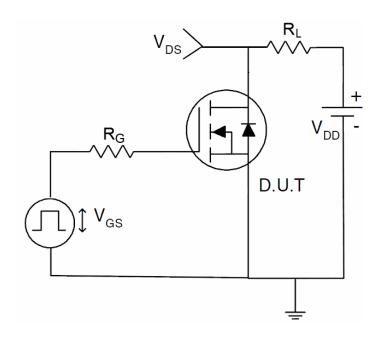
## 1) E<sub>AS</sub> Test Circuits



## 2) Gate Charge Test Circuit

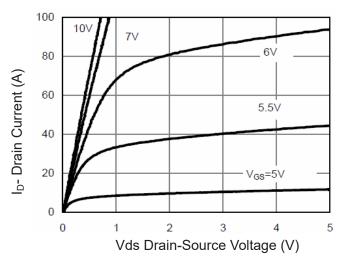


## 3) Switch Time Test Circuit

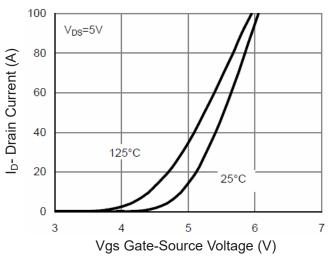




### Typical Electrical and Thermal Characteristics (Curves



**Figure 1 Output Characteristics** 



**Figure 2 Transfer Characteristics** 

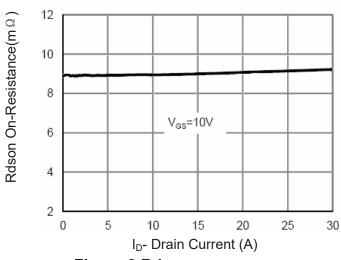
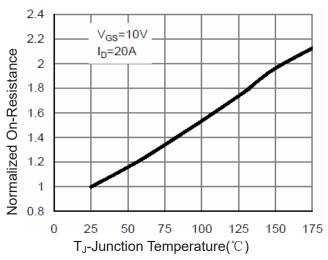


Figure 3 Rdson- Drain Current



**Figure 4 Rdson-Junction Temperature** 

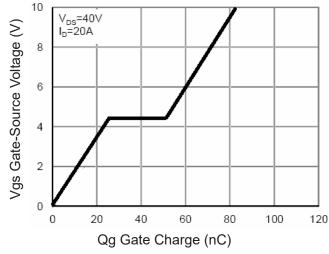


Figure 5 Gate Charge

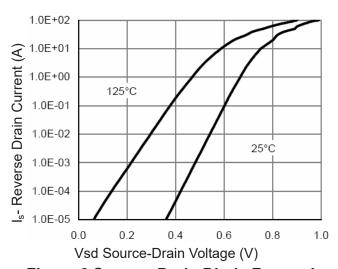
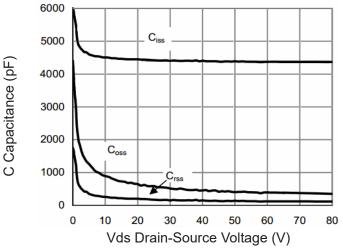


Figure 6 Source- Drain Diode Forward





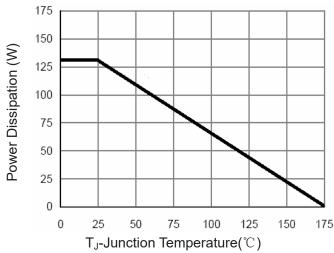
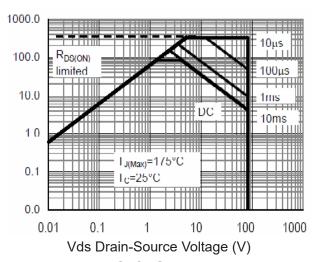


Figure 7 Capacitance vs Vds

Figure 9 Power De-rating



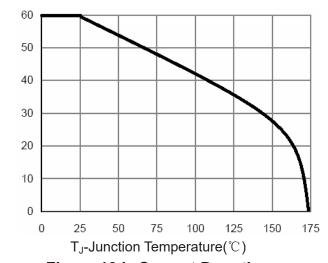
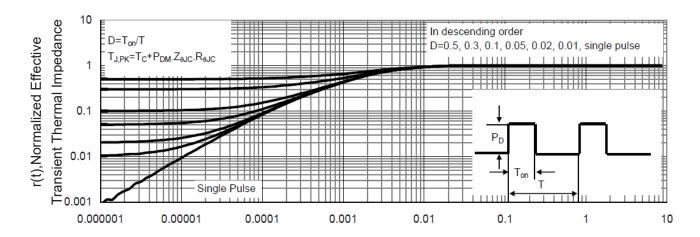


Figure 8 Safe Operation Area

Figure 10 I<sub>D</sub> Current De-rating



Drain Current (A)

Square Wave Pluse Duration(sec)

**Figure 11 Normalized Maximum Transient Thermal Impedance**